

# NIRSpec pipeline concept

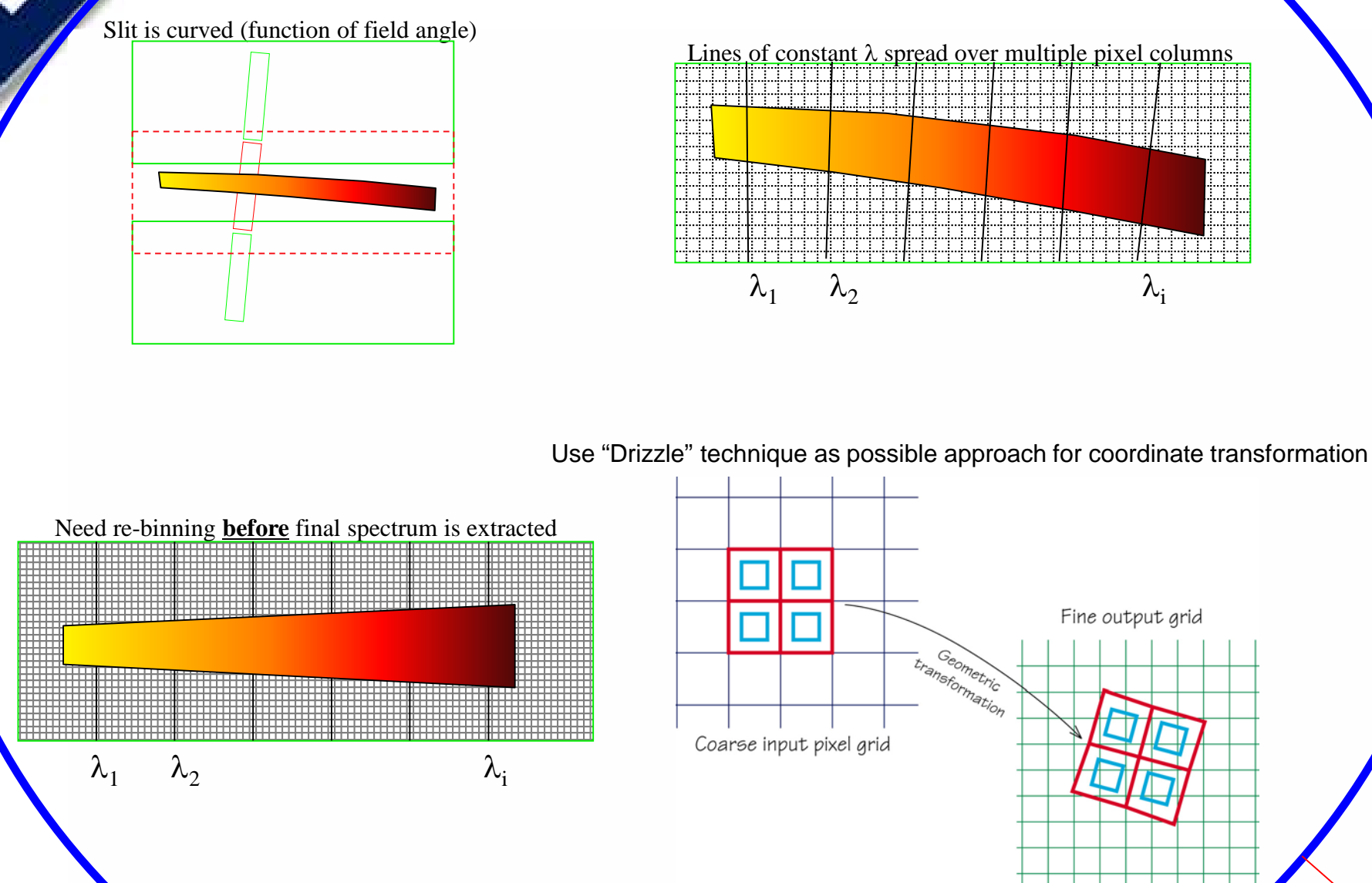
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### Instrument characteristics:

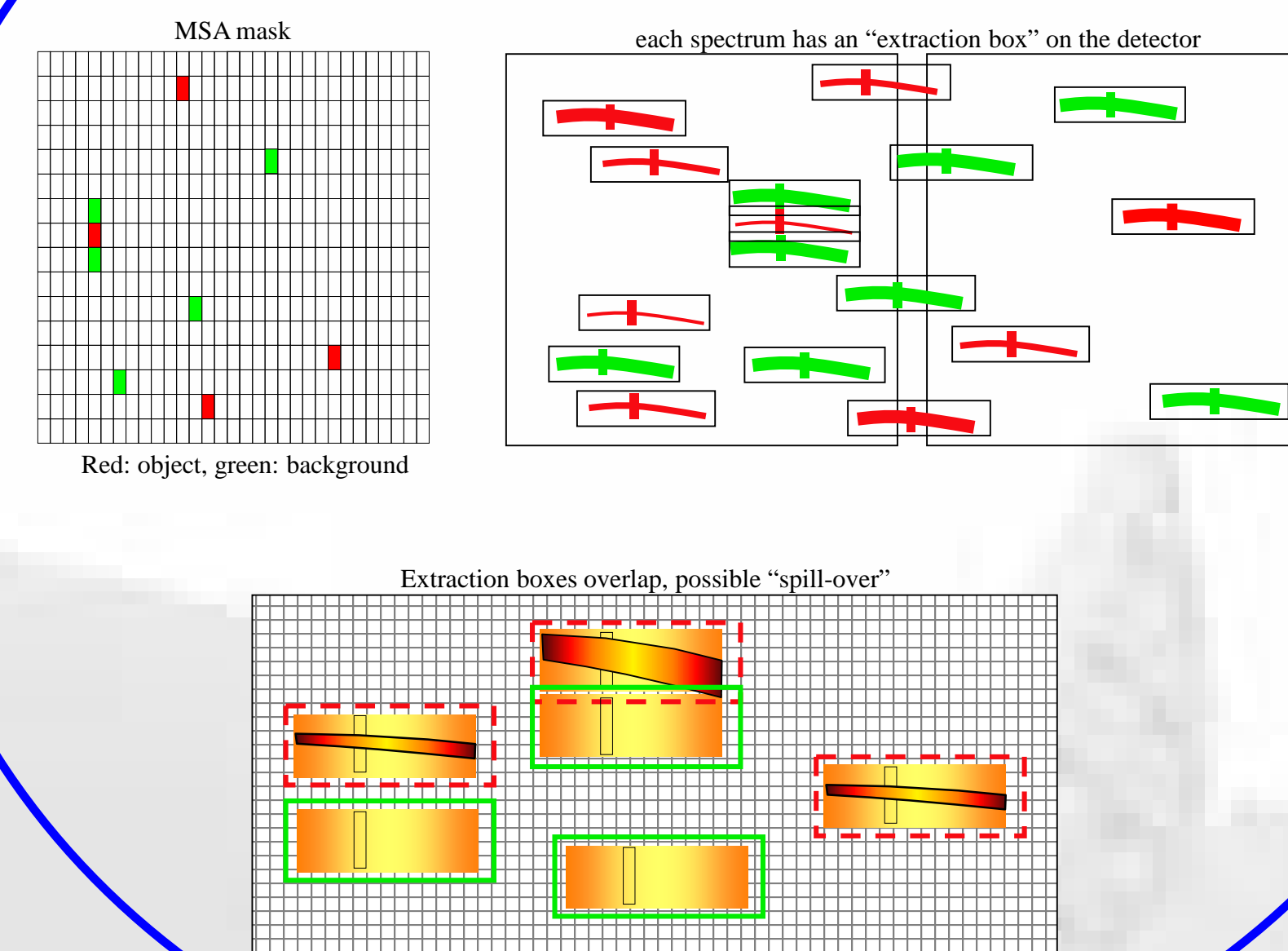
- 1) used on a diffraction-limited telescope --> PSF varies with  $\lambda$
- 2) wide wavelength range (0.6 - 5  $\mu\text{m}$ ) --> chromatic slit losses
- 3) off-axis telescope and wide field of view --> significant distortion
- 4) reflective optics (including dispersive elements) --> large, variable slit curvature
- 5) multi-object spectrograph --> every detector pixel sees every wavelength

Headaches....

### Rectifying NIRSpec Spectra

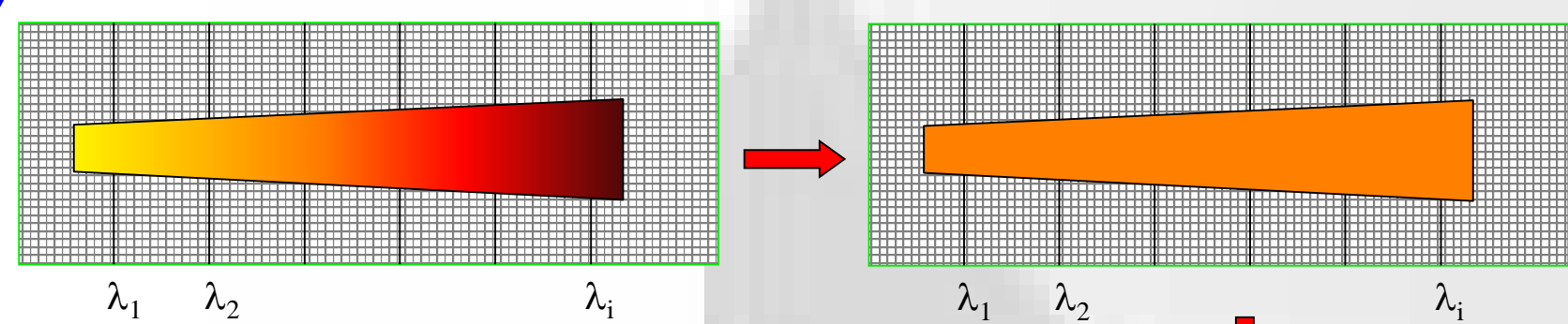


### Defining the extraction windows



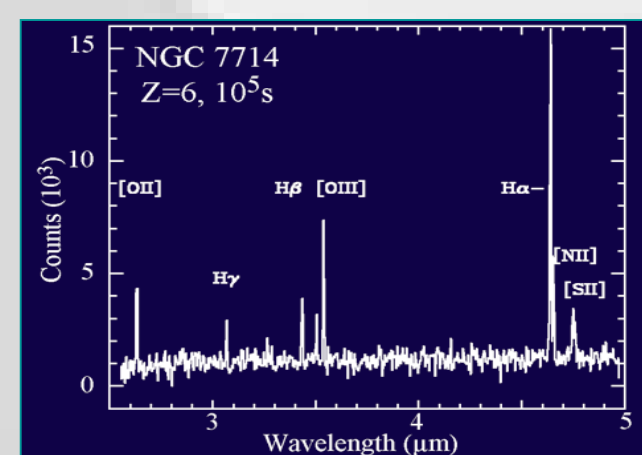
### "Delta" correction for chromatic slit loss

- depends on source shape and position within shutter
- must be user-controlled



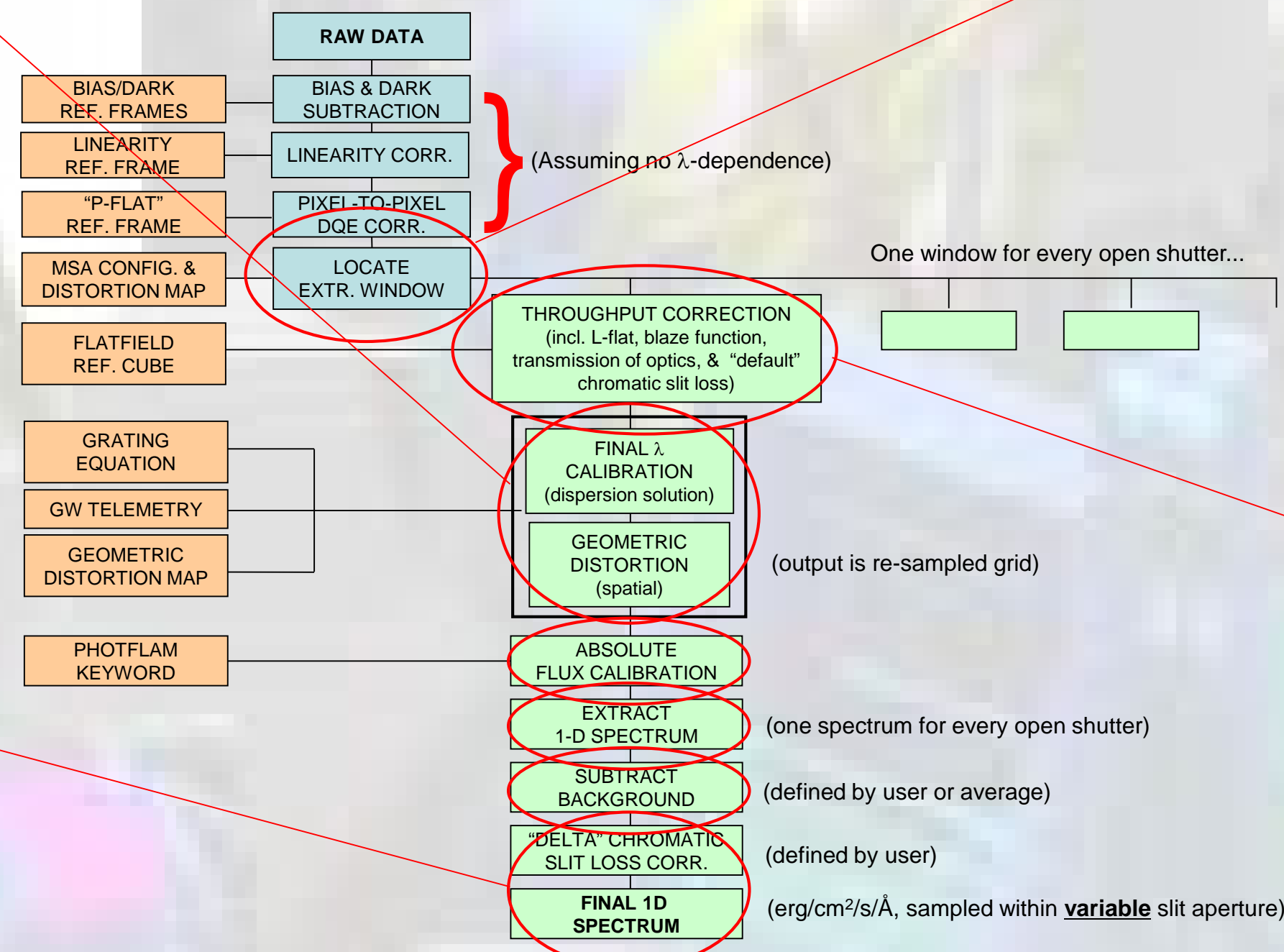
### Collapse to 1-D spectrum

- depends on source extent and background subtraction
- must be user-controlled



For quick-look analysis, pipeline subtracts TBD "default" background

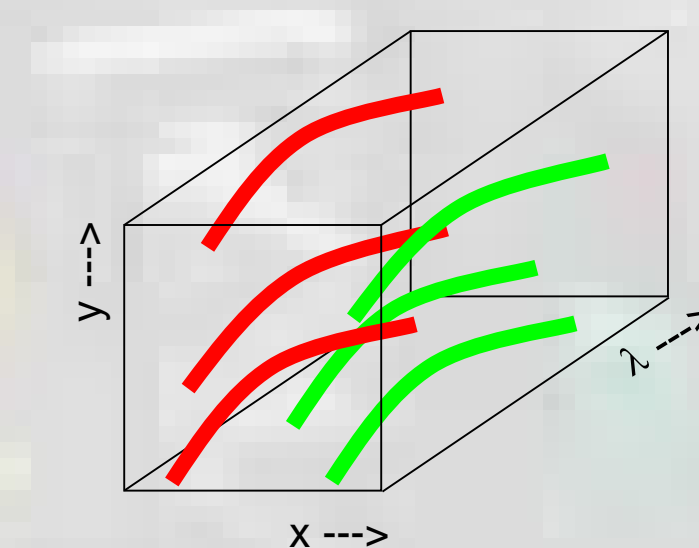
### An outline of the NIRSpec pipeline



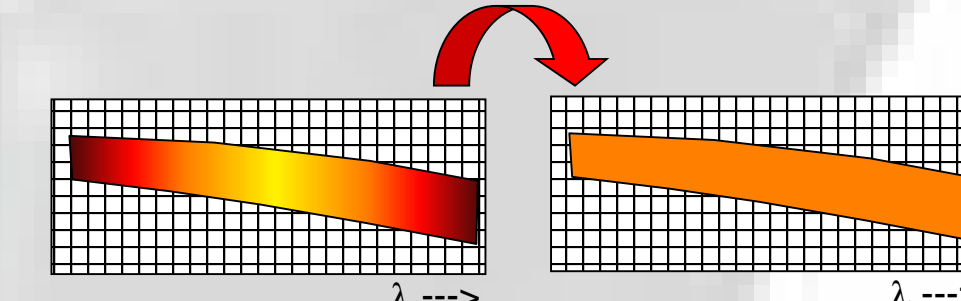
### "Flat-fielding" NIRSpec spectra

Throughput correction of

Need a "throughput" data cube (for each filter/grating combination)



Output: (assuming a source with flat spectrum)

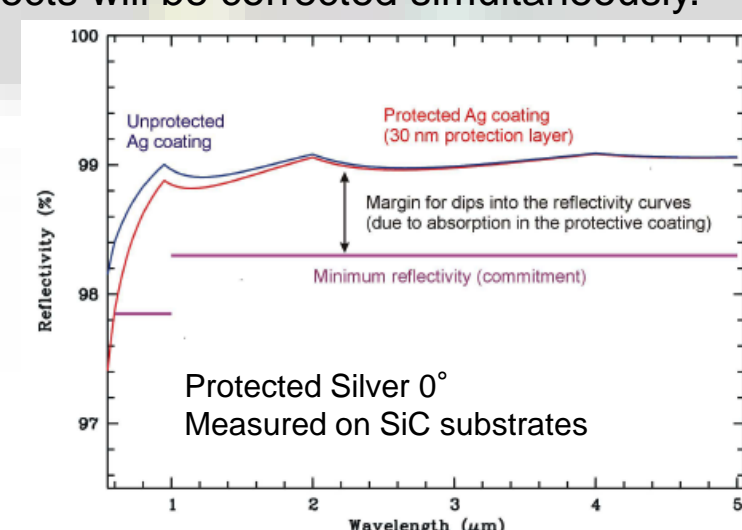


Goal: to correct for the total instrumental throughput variations, both as a function of wavelength (e.g. optics transmission, blaze function) and field angle (e.g. DQE, vignetting).

### Contributions to the "Throughput correction"

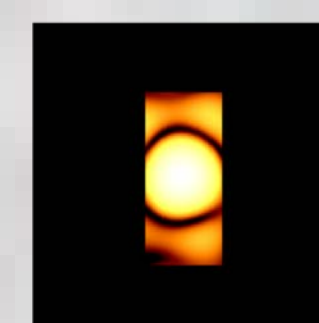
- reflection curves of all mirrors:  $f(\lambda)$ ,  $f(x,y)$
- transmission curves of filters:  $f(\lambda)$
- blaze function of grating:  $f(\lambda)$ ,  $f(x,y)$
- large-scale response of detector (L-flat):  $f(\lambda)$ ,  $f(x,y)$

All of these contributions need to be measured at component level and built into a physical/optical instrument model. Once NIRSpec is assembled, they cannot be measured individually. However, once a shutter has been specified, all of them are in principle - deterministic, and can be accurately modeled. Using the instrument model, all these effects will be corrected simultaneously.

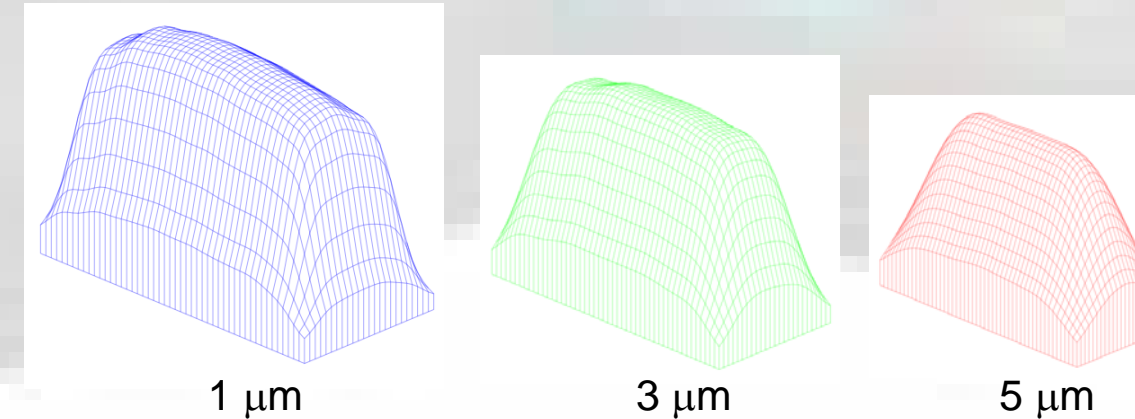


However...

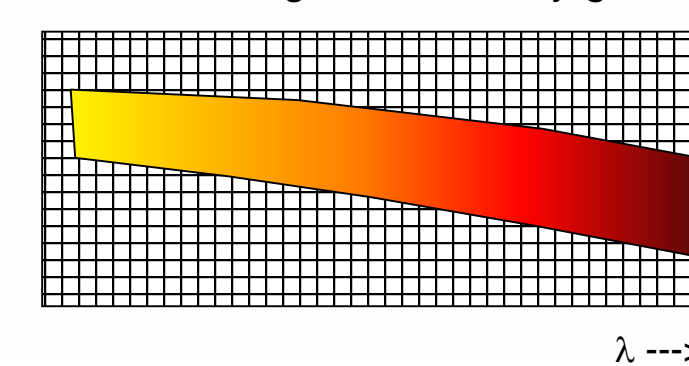
### The bummer: chromatic slit loss



Fixed slit size, but variable PSF width...



... causes "flaring" and intensity gradient



A "default" correction for e.g. a perfectly centered point source can be included in throughput correction. The user needs to optimise this correction at a later stage.